

# Photoacoustics metrology: Detection of grating underneath opaque metal and dielectric multilayers

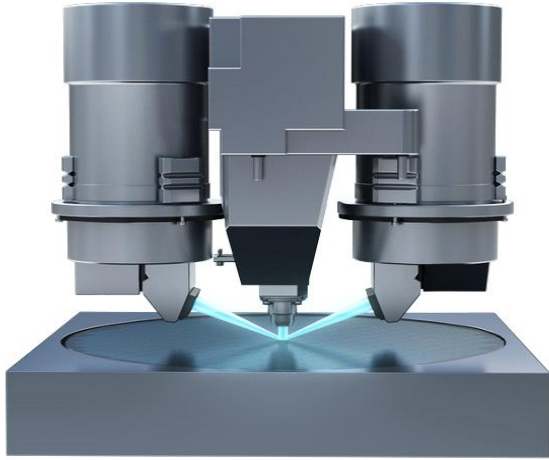
Stephen Edward, Hao Zhang, Vanessa Verrina,  
Alessandro Antoncetti, Stefan Witte, Paul Planken  
*ARCNL, Amsterdam*

Irwan Setija  
*ASML Research, Veldhoven*

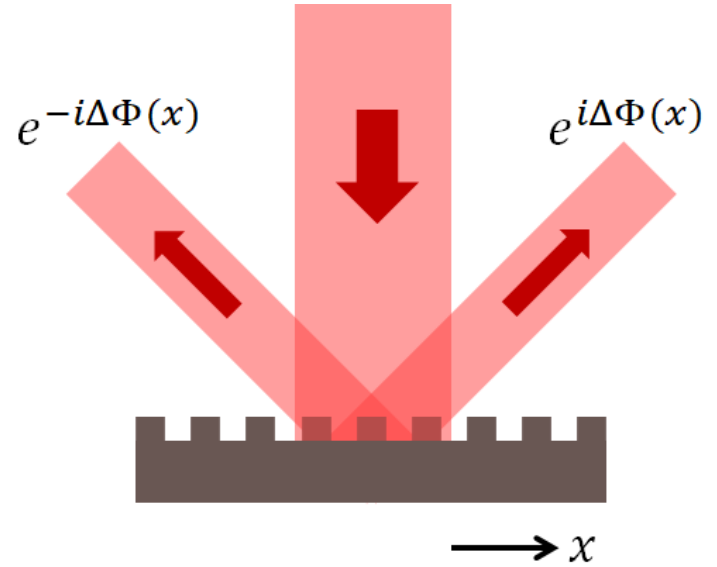


04 Nov 2019 | Amsterdam

# Motivation



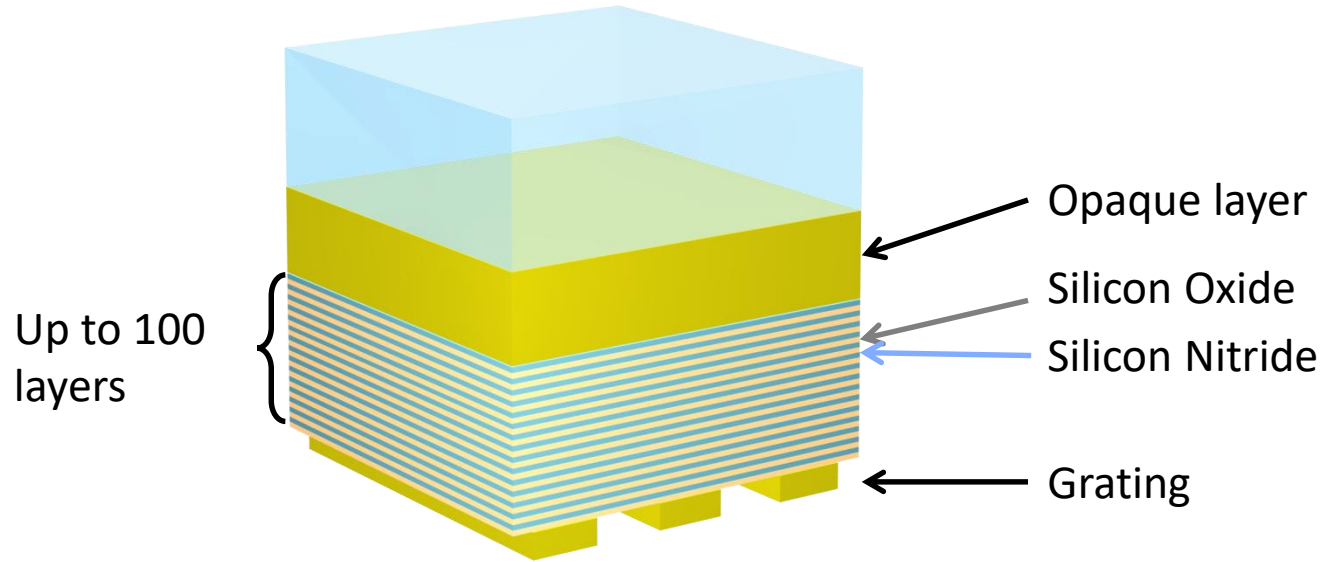
Gratings are required to position  
Si wafers accurately ( $< 1$  nm)



Grating displacement changes  
Optical phase of diffracted beams

# Motivation

Schematic of new 3D NAND memory chips



**Problem:** light cannot “see” grating through opaque layers

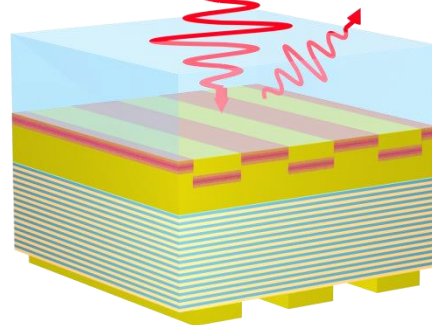
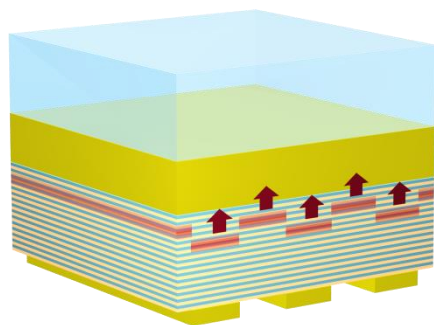
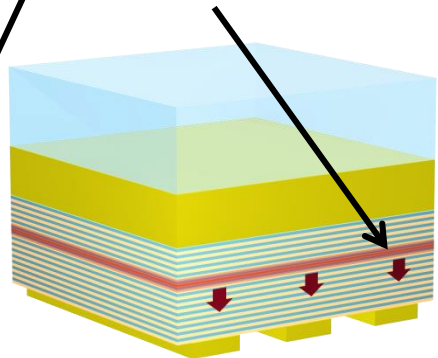
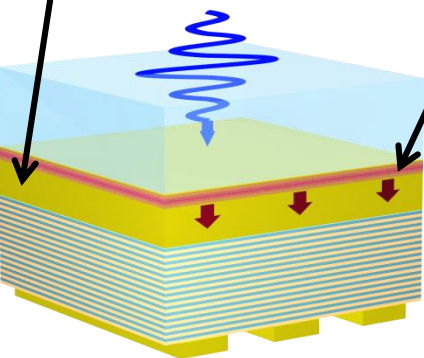
# Possible solution: Photoacoustics

Opaque material

pump

High frequency  
acoustic wave  
( $10^{10-11}$  Hz)

probe  
1<sup>st</sup> order  
diffraction



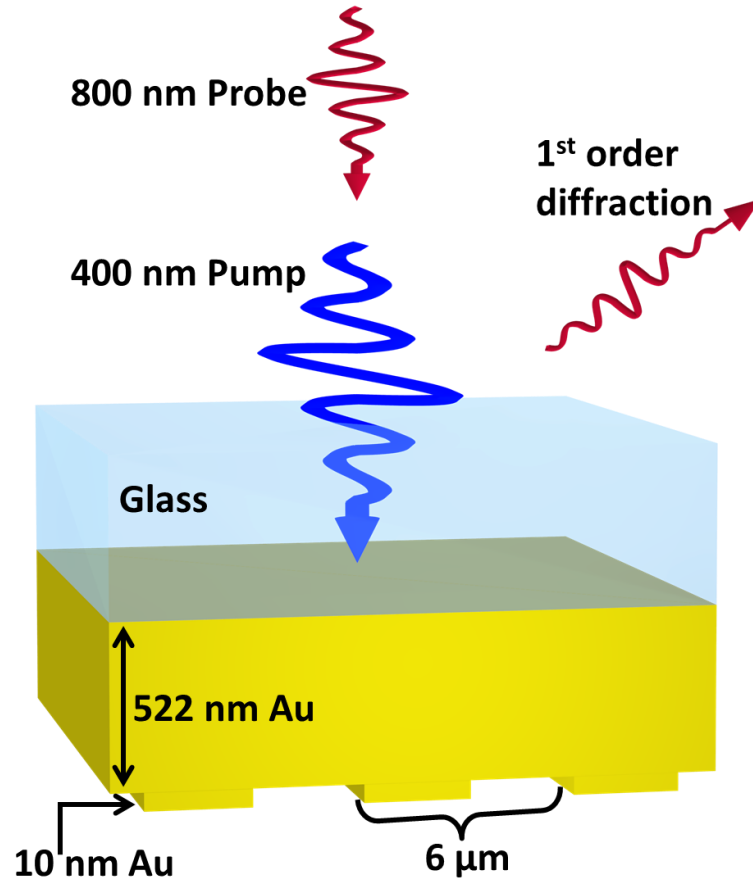
(1) Light absorption  
and acoustic wave  
generation

(2) Acoustic wave  
propagation

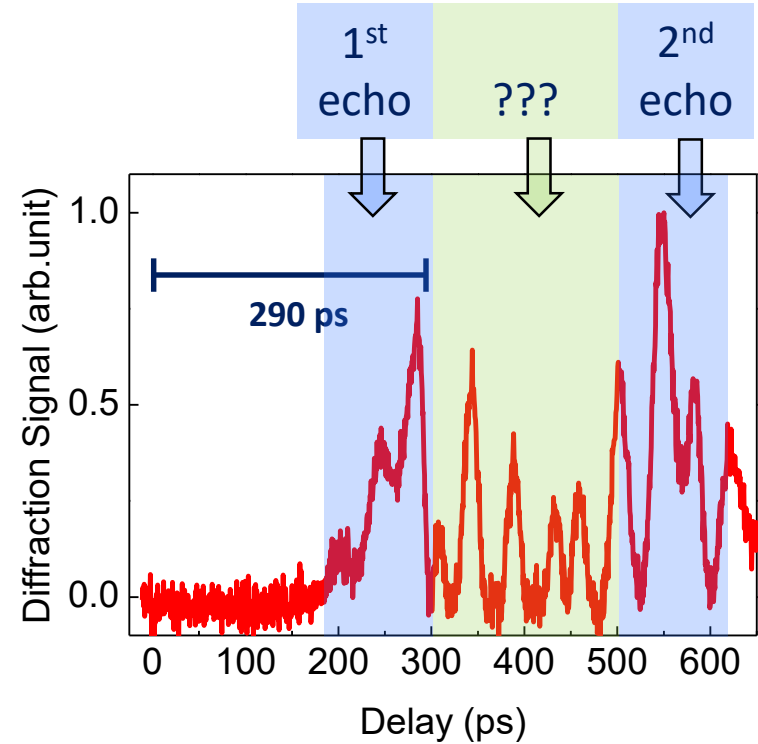
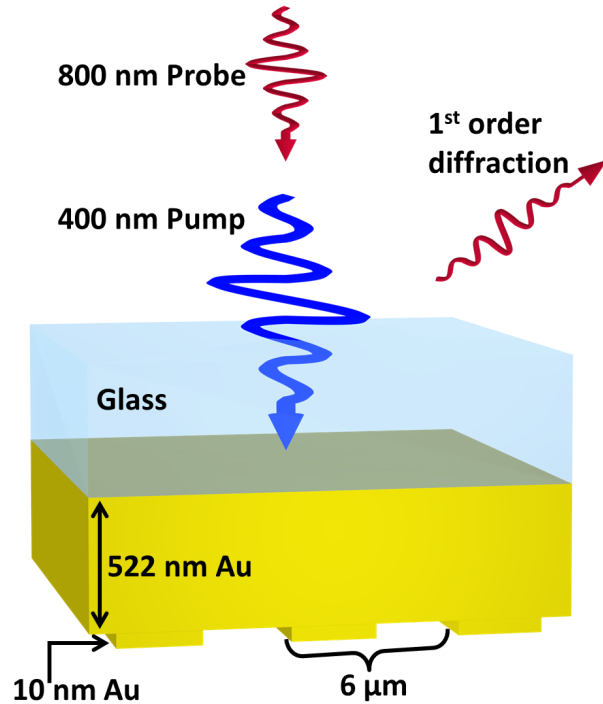
(3) Acoustic wave  
reflection off grating

(4) Acoustic wave  
induced grating at  
surface

# Acoustic echo from grating buried under Au

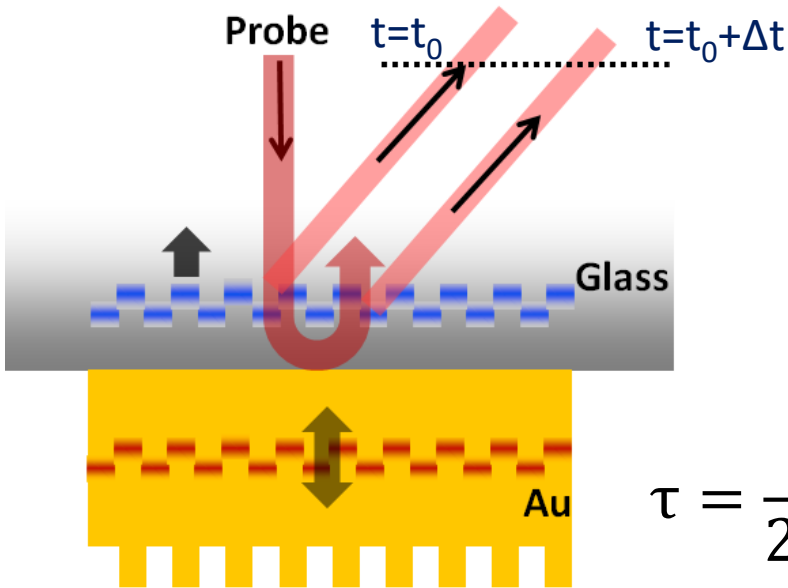


# Acoustic echo from grating buried under Au

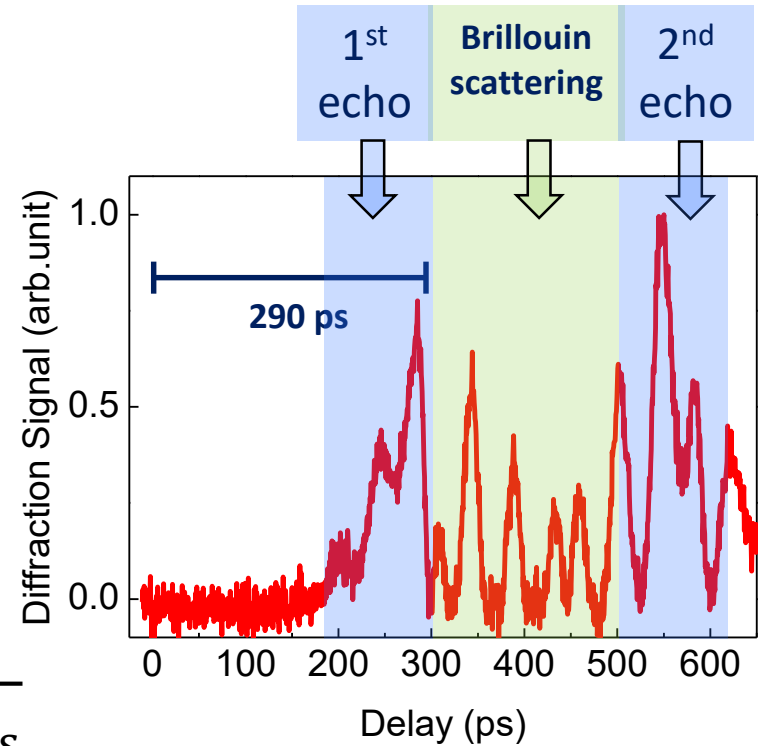


# Acoustic echo from grating buried under Au

**Brillouin scattering**: Interference between diffracted, and delayed-diffracted beams

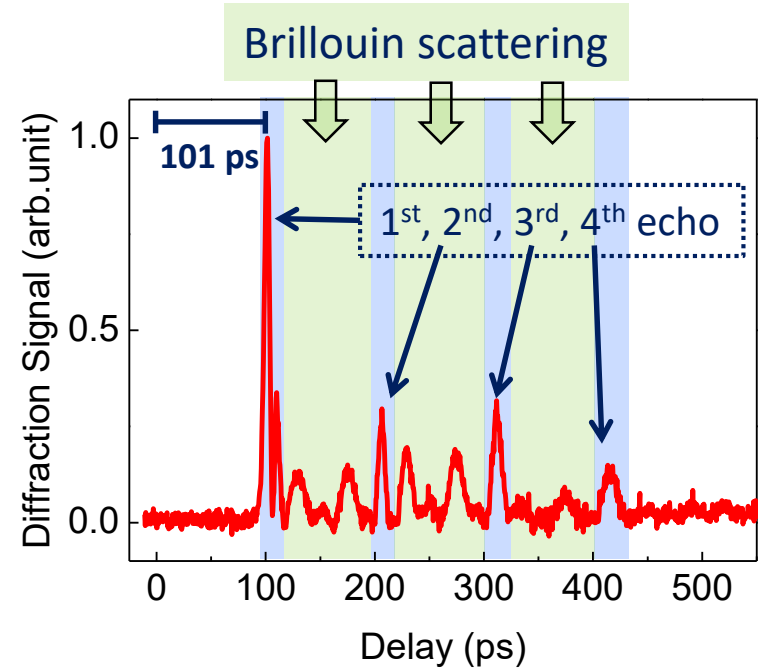
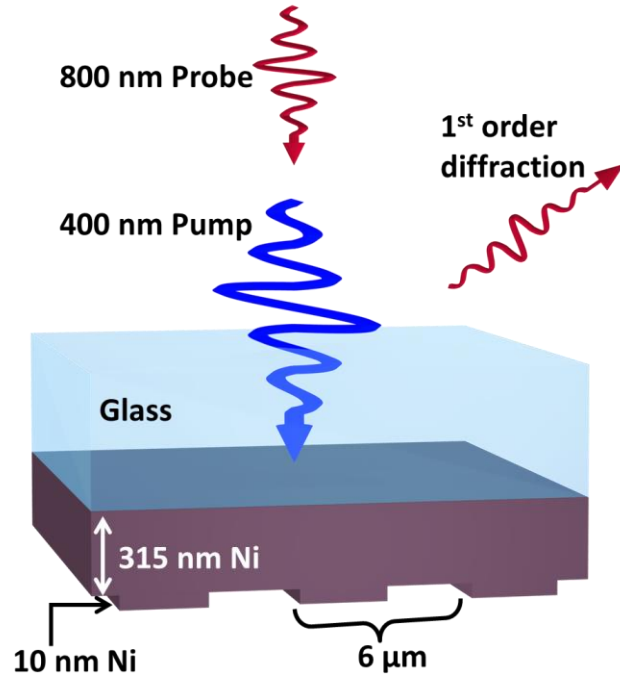


$$\tau = \frac{\lambda_{probe}}{2nv_{glass}}$$



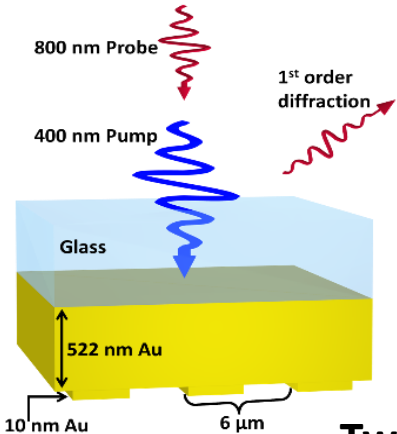
For 800 nm wavelength, the oscillation period is about 46 ps

# Acoustic echo from grating buried under Ni





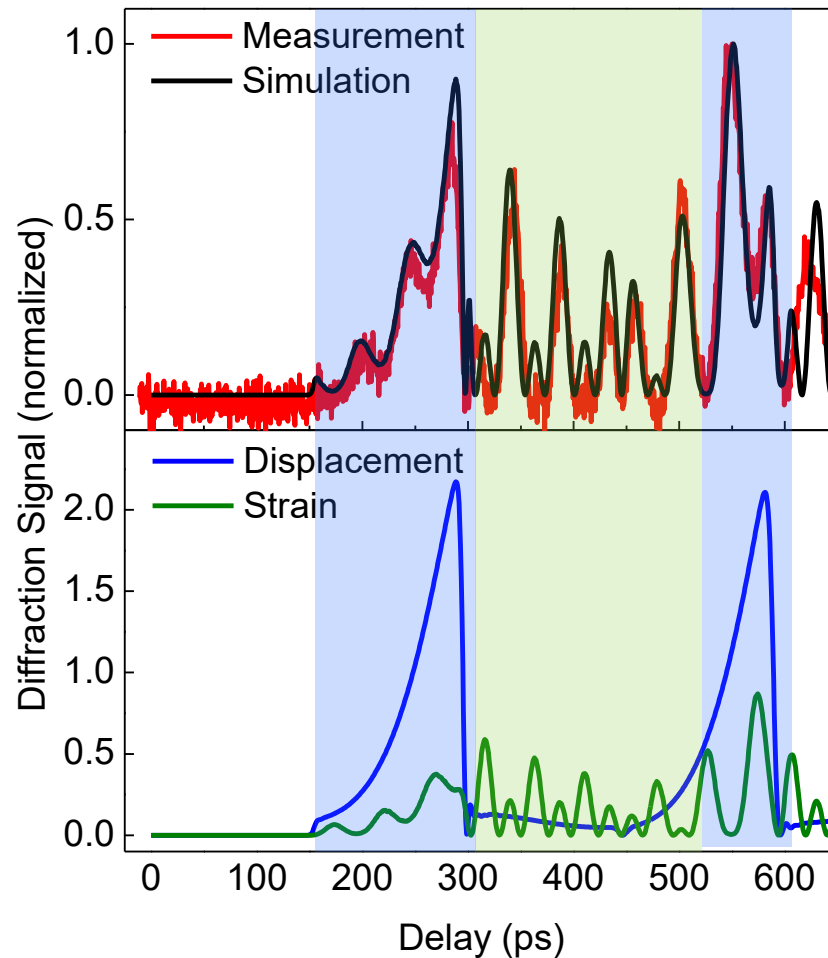
# Experiment and Simulation



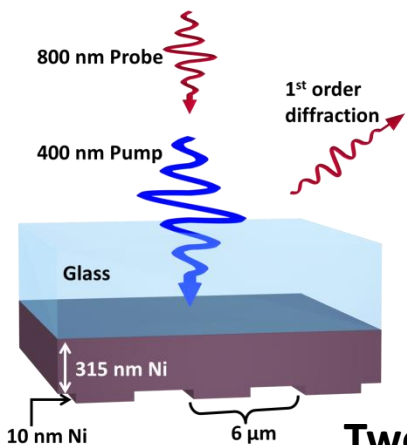
## Two contributions

- Displacement of metal atoms at the metal/glass interface
- Change in refractive index of the glass substrate

Cannot simply add diffracted intensities, diffracted fields must be added coherently



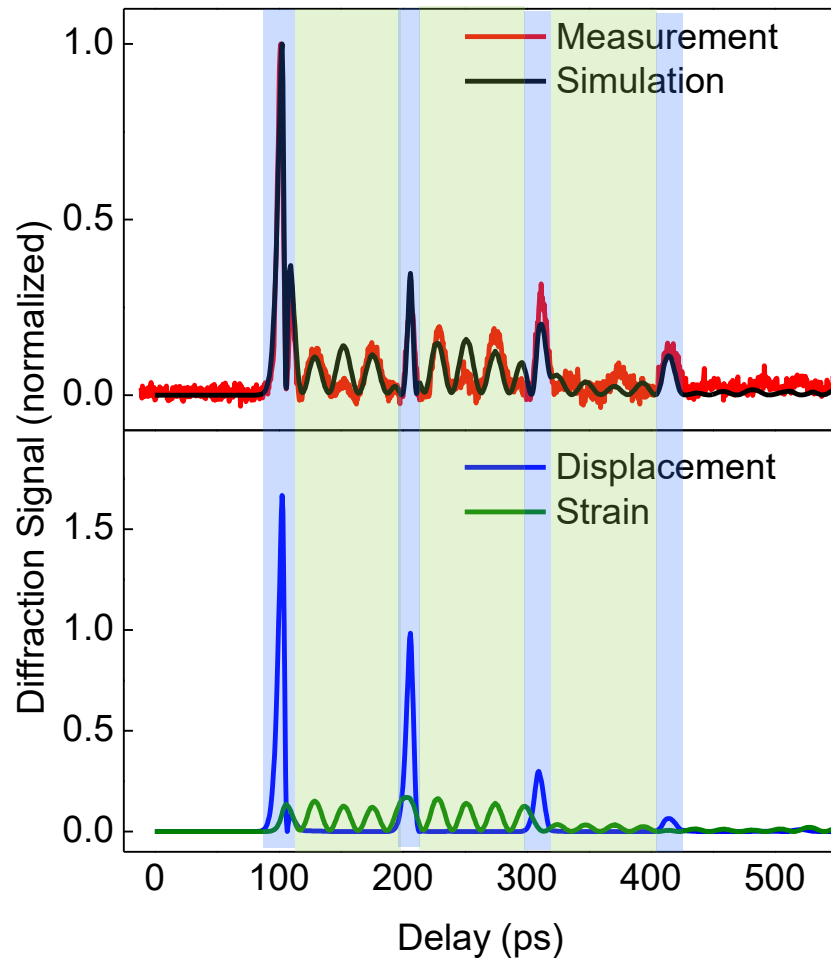
# Experiment and Simulation



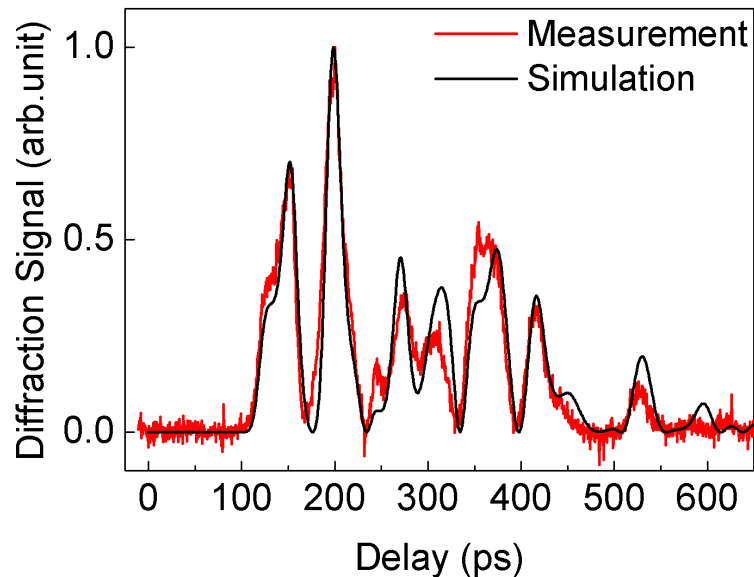
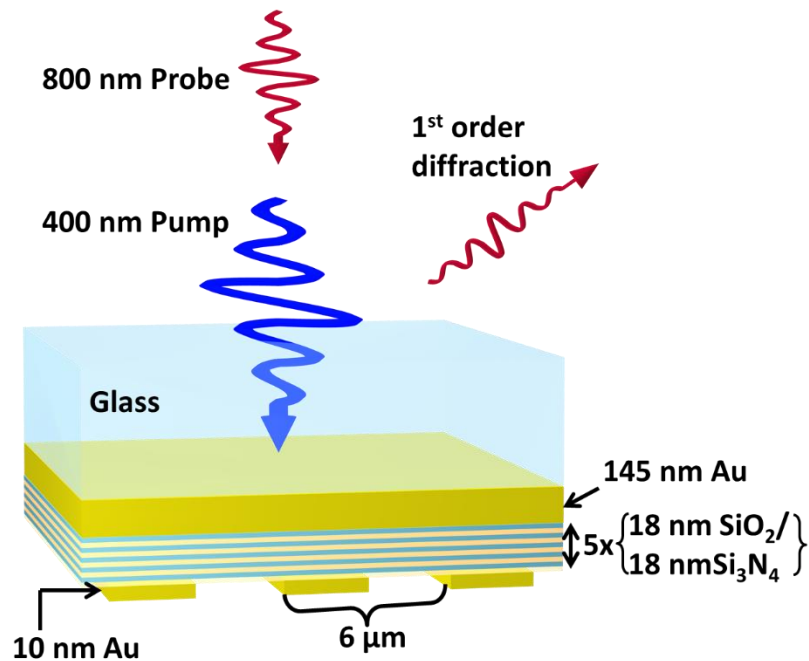
## Two contributions

- Displacement of metal atoms at the metal/glass interface
- Change in refractive index of the glass substrate

Cannot simply add diffracted intensities, diffracted fields must be added coherently

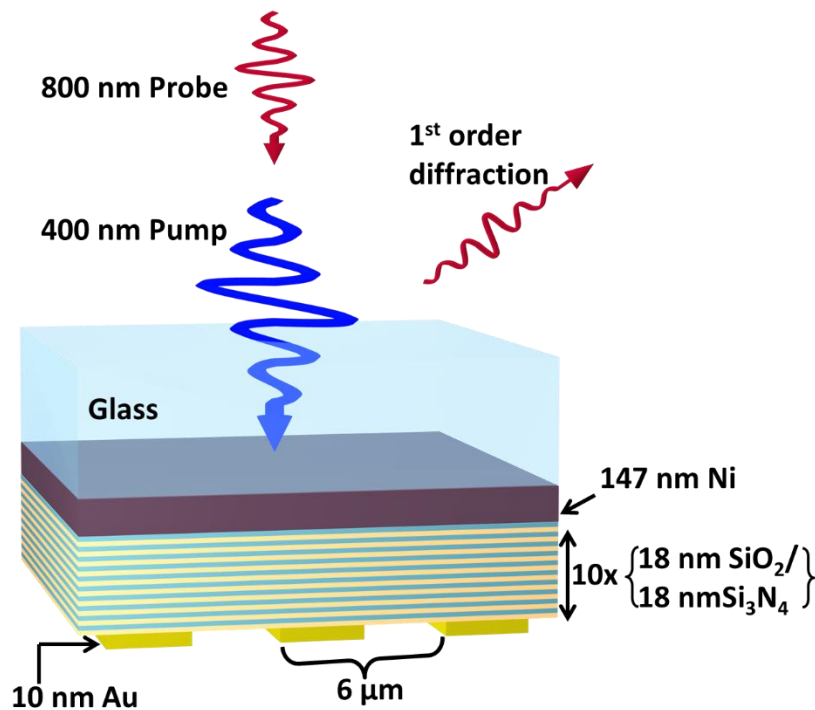


# Acoustic echoes from gratings under metals and dielectric

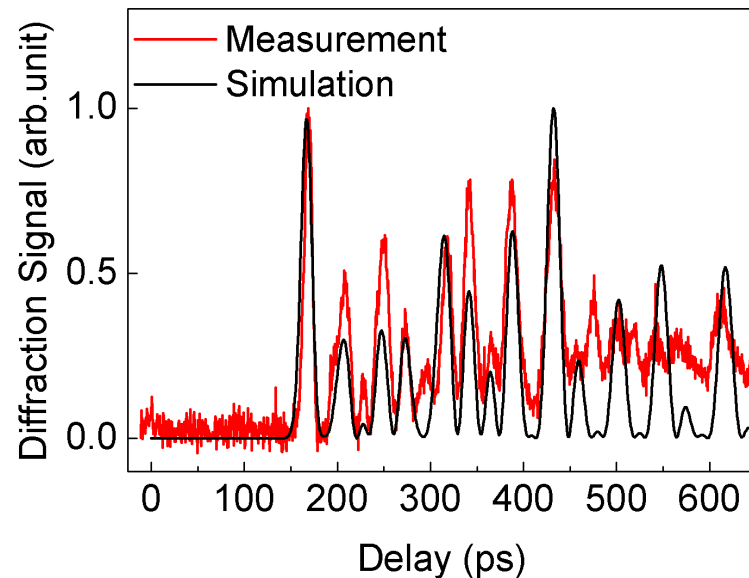


Grating still observed through multiple dielectric layers

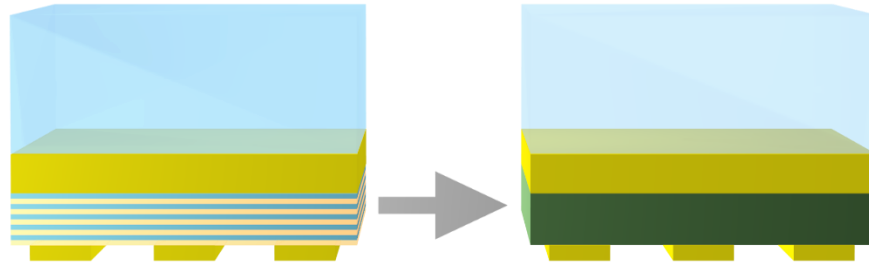
# Acoustic echoes from gratings under metals and dielectric



Grating still observed through multiple dielectric layers

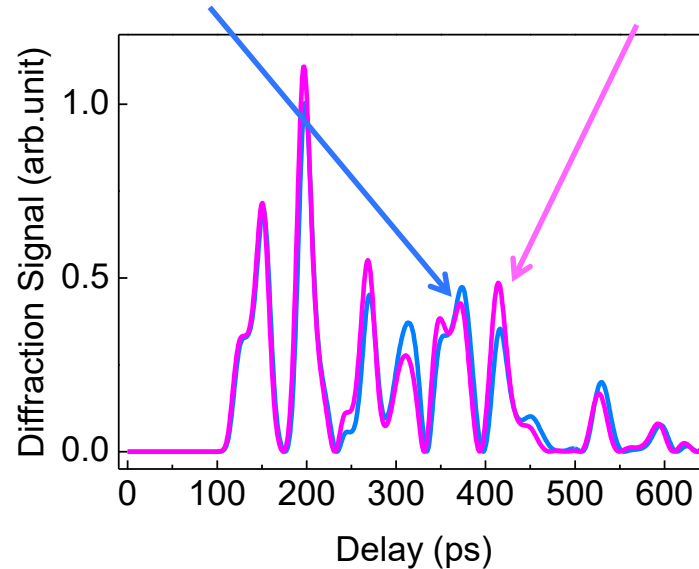


# Effect of multilayers in calculation

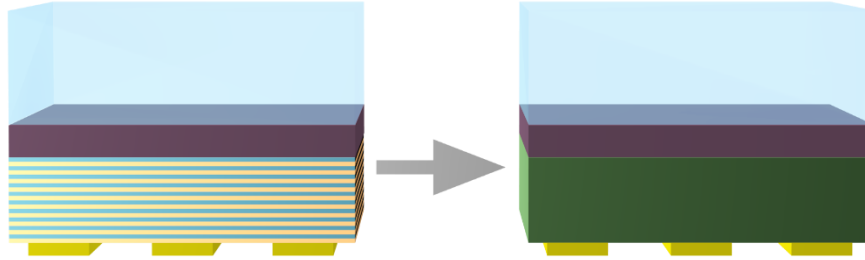


**10 dielectric layers → single, time averaged medium**

Acoustic wave "sees"  
an equivalent time-  
average medium rather  
than multiple layers.

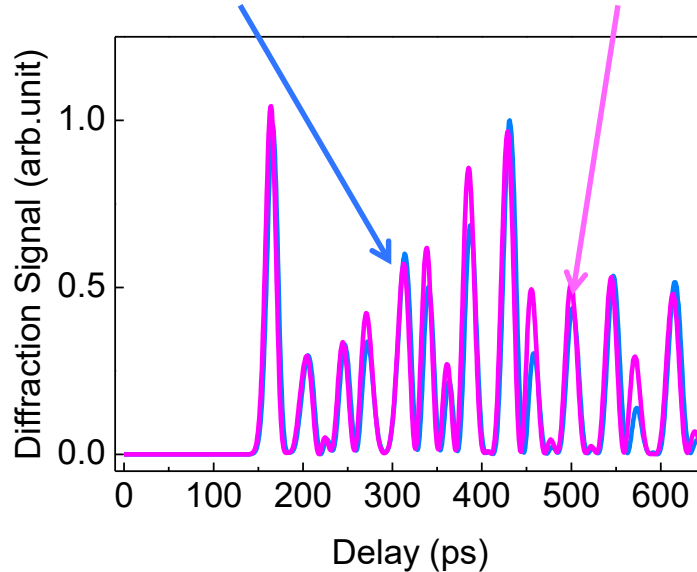


# Effect of multilayers in calculation



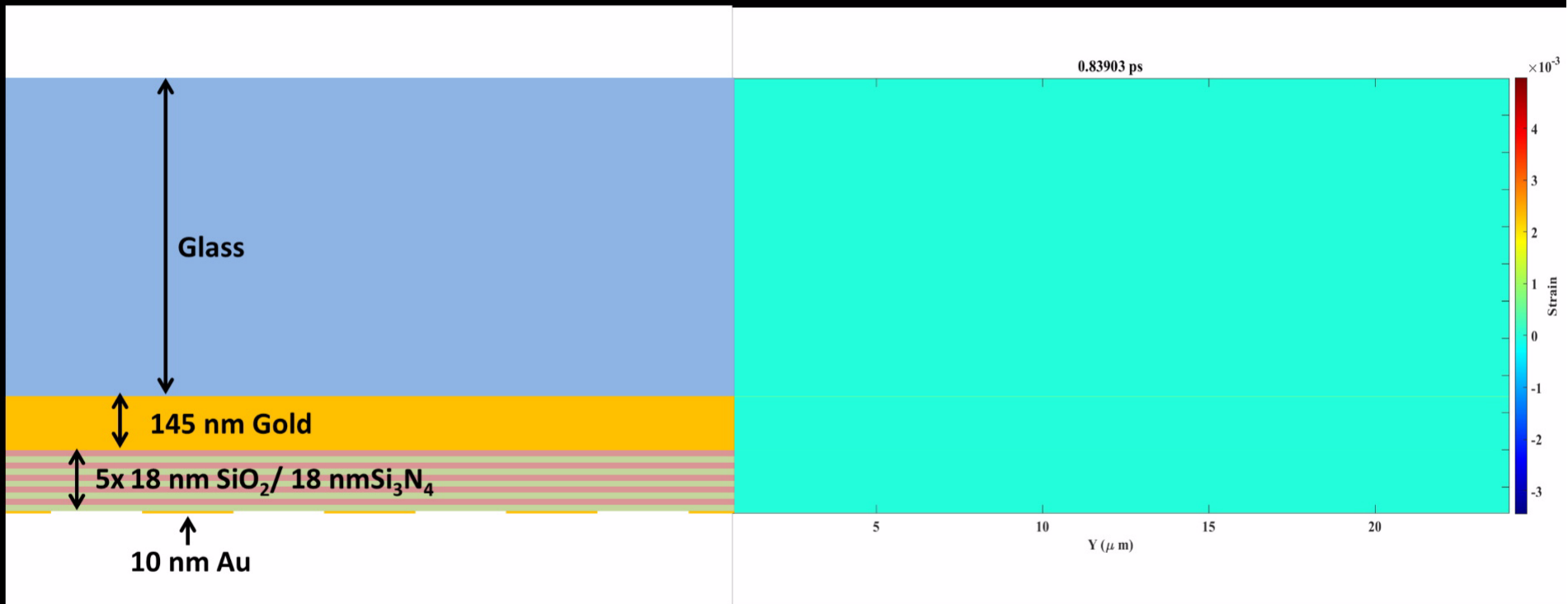
20 dielectric layers  $\rightarrow$  single, time averaged medium

Acoustic wave "sees" an equivalent time-average medium rather than multiple layers.



Multiple dielectric layer don't prevent us from using this technique in real-life semiconductor industry applications.

# Strain inside the Au multilayer sample



# Summary

- Detection of gratings buried underneath optically opaque metal/dielectric layers through its acoustic copy.
  - Grating underneath flat layer of Au and Ni.
  - Au grating underneath samples similar to a 3D NAND structure.
  - Multiple dielectric layers have very little effect on the shape and strength of diffracted signal.



# Acknowledgements

Group members:

Guido de Haan

Thomas Meijvogel

From ASML:

Bas Goorden

Simon Huisman

ASML



UNIVERSITEIT VAN AMSTERDAM

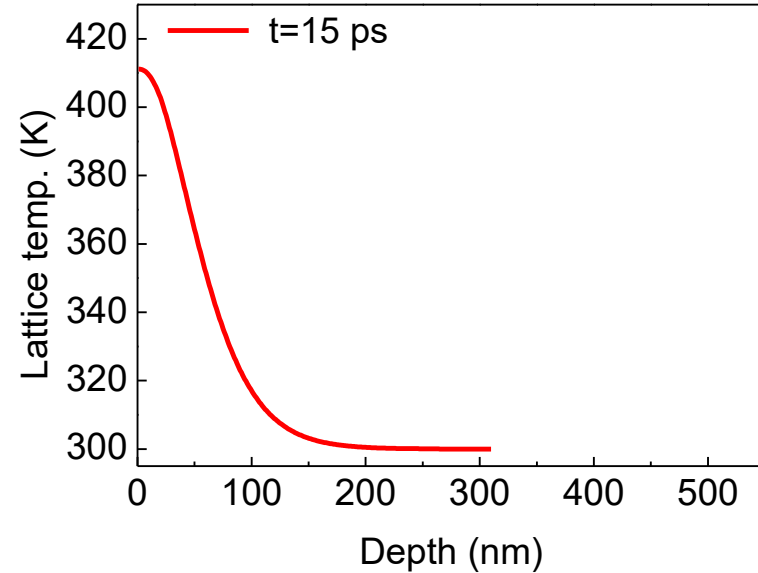
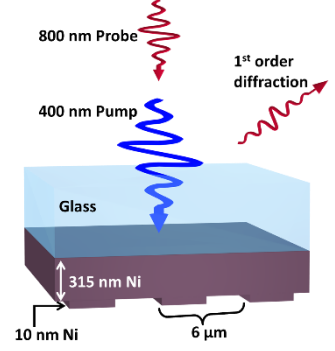
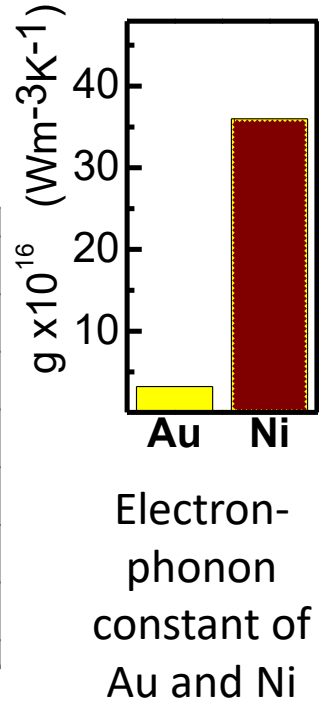
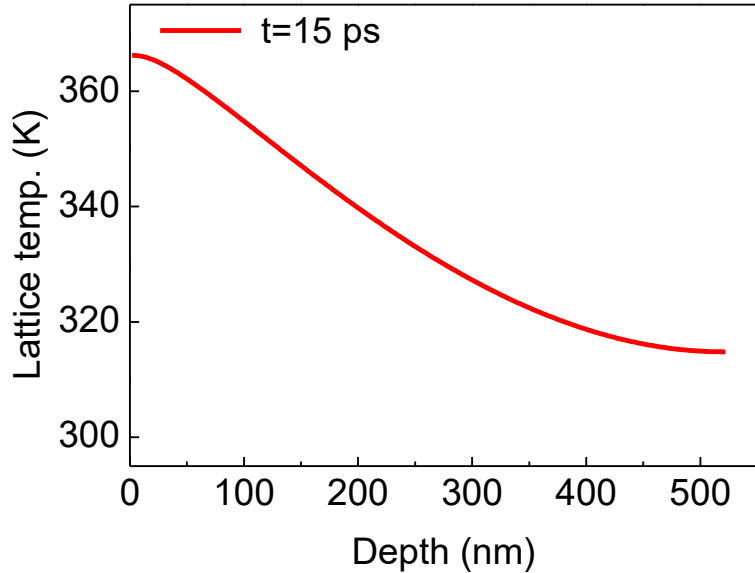
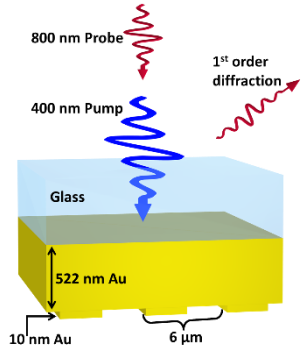


ADVANCED RESEARCH CENTER FOR NANOLITHOGRAPHY

# References

- O. Matsuda, M. C. Larciprete, R. L. Voti, O. B. Wright, *Ultrasonics* 56 (2015) 3–20
- P. Ruello, V. E. Gusev, *Ultrasonics* 56 (2015) 21–35
- A. Devos , *Ultrasonics* 56 (2015) 90–97
- A. A. Maznev, F. Hofmann, J. Cuffe, J. K. Eliason, K. A. Nelson, *Ultrasonics* 56 (2015) 116-121
- Timothy F. Crimmins, A. A. Maznev, and Keith A. Nelson, *Applied Physics Letters* 74, 1344 (1999);
- Hohlfeld et al. *Appl. Phys. B* 64, 387 (1997)
- C. Thomsen, H.T. Grahn, H.J. Maris, J. Tauc, *Phys. Rev. B* 34 (1996) 4129.
- O.B. Wright, K. Kawashima, *Phys. Rev. Lett.* 69 (1992) 1668.
- S.A. Akmanov, V.E. Gusev, *Sov. Phys. Usp.* 35 (1992) 153.
- V.E. Gusev, A.A. Karabutov, *Laser Optoacoustics*, American Institute of Physics, Woodbury, NY, 1993.

# Optical excitation of Au and Ni layers



Optical energy is deposited in smaller volume for Nickel, hence contains higher frequencies